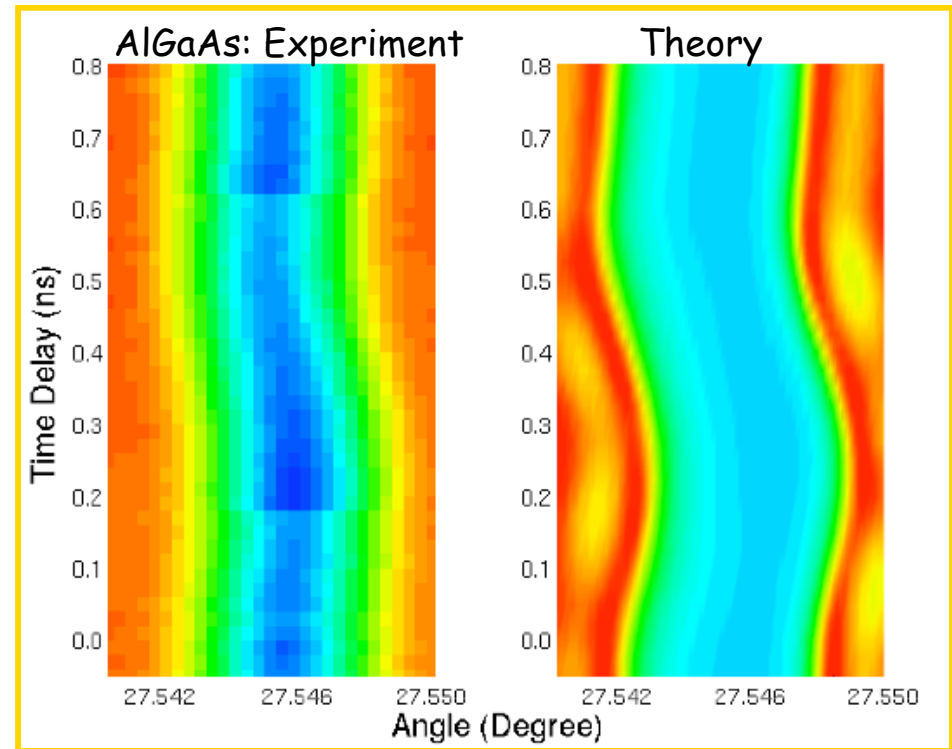
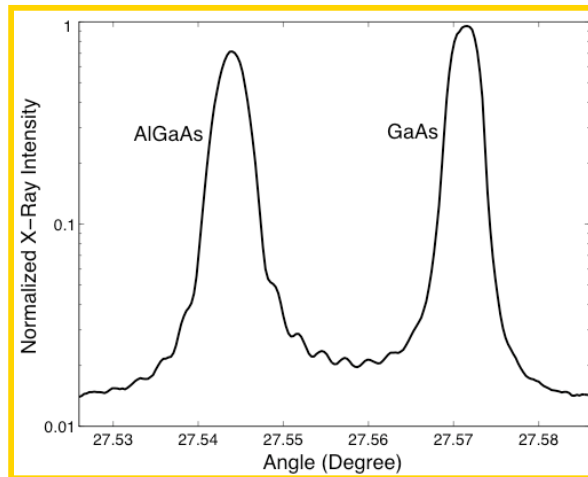


Ultrafast X-ray Diffraction Measurements of Nanoscale Thermal Transport

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- Interface dynamics
- Thin Film Properties
- Electron Phonon Coupling



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